

N-Channel Enhancement Mode Power MOSFET

DESCRIPTION

The HM2302KR uses advanced trench technology to provide excellent $R_{\rm DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

GENERAL FEATURES

V_{DS} = 20V,I_D = 2.9A

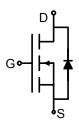
 $R_{DS(ON)}$ < 59m Ω @ V_{GS} =2.5V

 $R_{DS(ON)} < 45m\Omega$ @ V_{GS} =4.5V

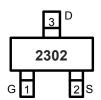
- High Power and current handing capability
- Lead free product is acquired
- Surface Mount Package

Application

- Battery protection
- Load switch
- Power management



Schematic diagram



Marking and pin Assignment



SOT-323 top view

Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
2302	HM2302KR	SOT-323	Ø180mm	8 mm	3000 units

Absolute Maximum Ratings (TA=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	VDS	20	V
Gate-Source Voltage	V _{GS}	±10	V
Drain Current-Continuous	I _D	2.9	Α
Drain Current-Pulsed (Note 1)	I _{DM}	10	Α
Maximum Power Dissipation	P _D	1	W
Operating Junction and Storage Temperature Range	T_{J}, T_{STG}	-55 To 150	$^{\circ}$

Thermal Characteristic

Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{\theta JA}$	125	°C/W	l
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Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250μA	20	22	-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V,V _{GS} =0V	-	-	1	μA

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Gate-Body Leakage Current	I _{GSS}	V _{GS} =±10V,V _{DS} =0V	-	-	±100	nA
On Characteristics (Note 3)						
Gate Threshold Voltage	Threshold Voltage $V_{GS(th)}$ $V_{DS}=V_{GS}$, $I_D=250\mu$		0.5	0.75	1.2	V
Drain-Source On-State Resistance	В	V _{GS} =2.5V, I _D =2.5A	-	37	59	mΩ
Dialii-Source Oil-State Resistance	R _{DS(ON)}	V _{GS} =4.5V, I _D =2.9A	-	30	45	mΩ
Forward Transconductance	g FS	S V _{DS} =5V,I _D =2.9A		8	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C _{lss}	V _{DS} =10V,V _{GS} =0V,	-	300	-	PF
Output Capacitance	Coss	V _{DS} -10V,V _{GS} -0V, F=1.0MHz	-	120	-	PF
Reverse Transfer Capacitance	C _{rss}	F = 1.0WH12	-	80	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	10	15	nS
Turn-on Rise Time	t _r	V_{DD} =10 V , I_D =2.9 A	-	50	85	nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =4.5 V , R_{GEN} =6 Ω	-	17	45	nS
Turn-Off Fall Time	t _f		-	10	20	nS
Total Gate Charge	Qg	\/ -40\/ -2.04	-	4.0	10	nC
Gate-Source Charge	Q _{gs}	V_{DS} =10V, I_{D} =2.9A, V_{GS} =4.5V	-	0.65	-	nC
Gate-Drain Charge	Q_{gd}	v _{GS} -4.5v	-	1.2	-	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =2.9A	-	0.75	1.2	V
Diode Forward Current (Note 2)	Is		-	-	2.9	Α
					1	

Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width ≤ 300μ s, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

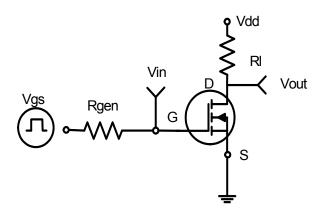


Figure 1:Switching Test Circuit

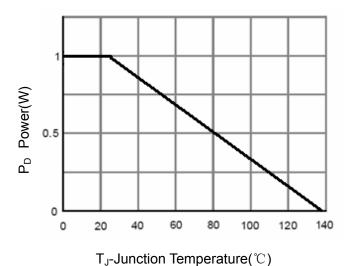


Figure 3 Power Dissipation

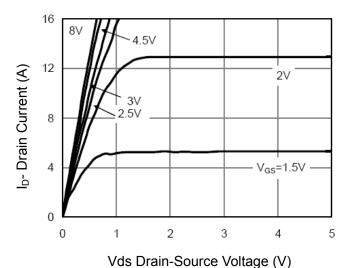


Figure 5 Output CHARACTERISTICS

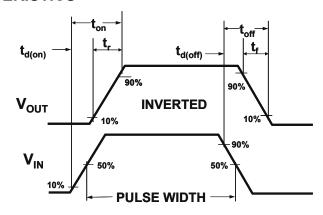
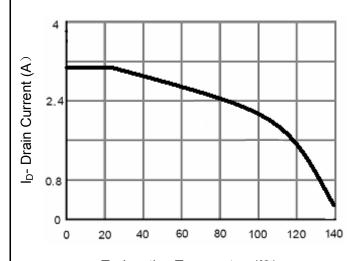


Figure 2:Switching Waveforms



T_J-Junction Temperature(°C)

Figure 4 Drain Current

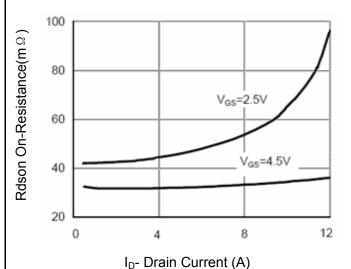


Figure 6 Drain-Source On-Resistance

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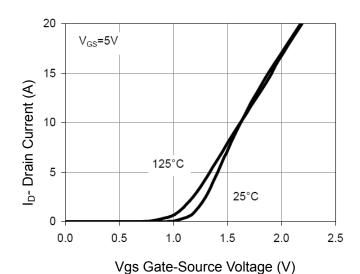
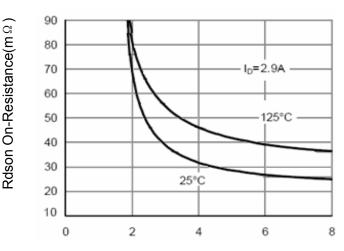


Figure 7 Transfer Characteristics



Vgs Gate-Source Voltage (V)

Figure 9 Rdson vs Vgs

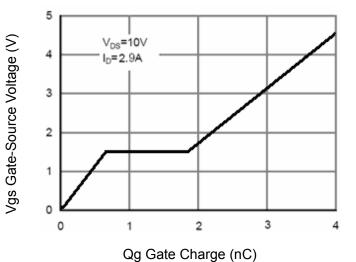
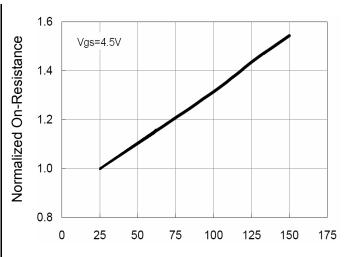
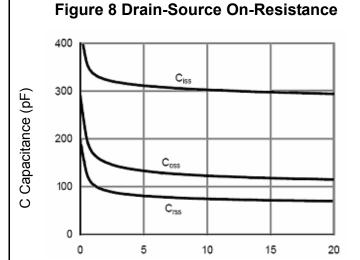


Figure 11 Gate Charge



 T_J -Junction Temperature($^{\circ}$ C)



Vds Drain-Source Voltage (V)

Figure 10 Capacitance vs Vds

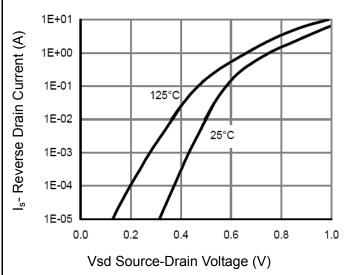
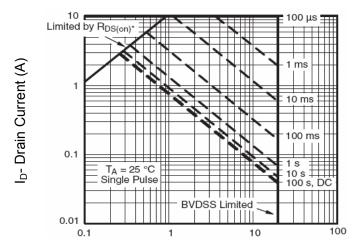


Figure 12 Source- Drain Diode Forward

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Vds Drain-Source Voltage (V)

Figure 13 Safe Operation Area

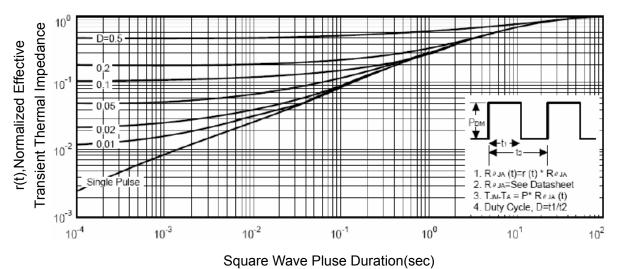
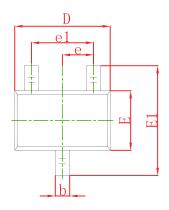
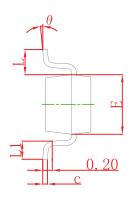
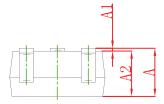


Figure 14 Normalized Maximum Transient Thermal Impedance

SOT-323 Package Outline Dimensions

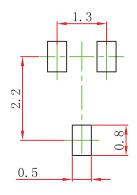






Sumbal	Dimensions	In Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	0.900	1.100	0.035	0.043	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.000	0.035	0.039	
b	0.200	0.400	0.008	0.016	
С	0.080	0.150	0.003	0.006	
D	2.000	2.200	0.079	0.087	
E	1.150	1.350	0.045	0.053	
E1	2.150	2.450	0.085	0.096	
е	0.650) TYP	0.026 TYP		
e1	1.200	1.400	0.047	0.055	
L	0.525	REF	0.021 REF		
L1	0.260	0.460	0.010	0.018	
θ	0°	8°	0°	8°	

SOT-323 Suggested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:±0.05mm.
- 3. The pad layout is for reference purposes only.

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